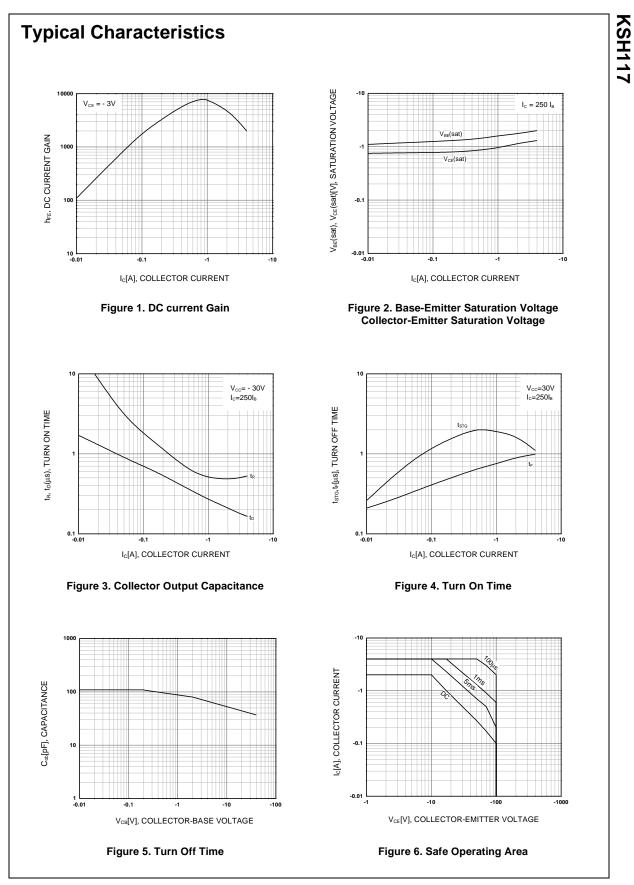


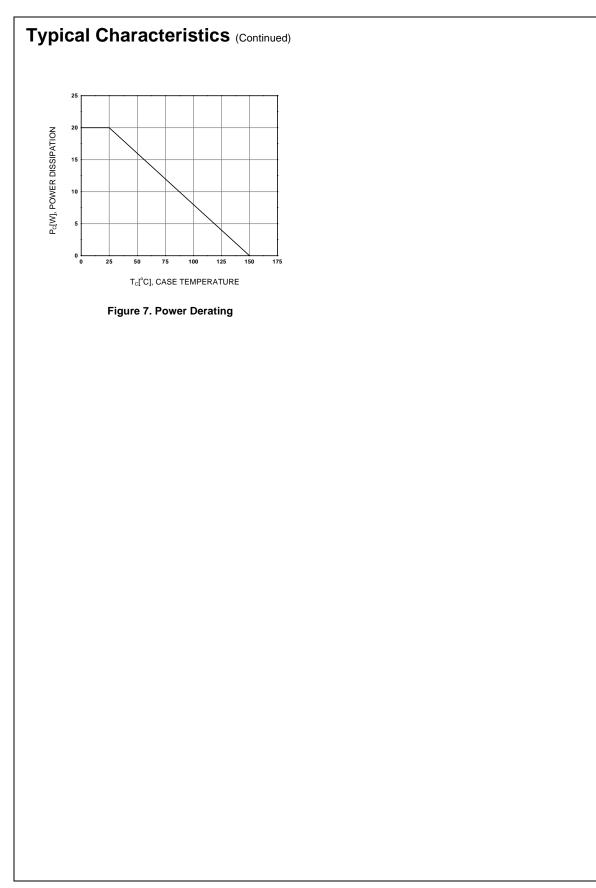
Symbol	Parameter	Test Condition	Min.	Max.	Units
V <sub>CEO</sub> (sus)	*Collector-Emitter Sustaining Voltage	I <sub>C</sub> = - 30mA, I <sub>B</sub> = 0	- 100		V
I <sub>CEO</sub>	Collector Cut-off Current	$V_{CE} = -50V, I_B = 0$		- 20	μA
I <sub>CBO</sub>	Collector Cut-off Current	$V_{CB} = -100V, I_E = 0$		- 20	μA
I <sub>EBO</sub>	Emitter Cut-off Current	$V_{EB} = -5V, I_{C} = 0$		- 2	mA
h <sub>FE</sub>	*DC Current Gain	$V_{CE} = - 3V, V_{EB} = - 0.5A$ $V_{CE} = - 3V, V_{EB} = - 2A$ $V_{CE} = - 3V, I_C = - 4A$	500 1000 200	12K	
V <sub>CE</sub> (sat)	*Collector-Emitter Saturation Voltage	$I_{C} = -2A, I_{B} = -8mA$ $I_{C} = -4A, I_{B} = -40mA$		- 2 - 3	V V
V <sub>BE</sub> (sat)	*Base-Emitter Saturation Voltage	I <sub>C</sub> = - 4A, I <sub>B</sub> = - 40mA		- 4	V
V <sub>BE</sub> (on)	*Base-Emitter On Voltage	V <sub>CE</sub> = - 3A, I <sub>C</sub> = - 2A		- 2.8	V
f <sub>T</sub>	Current Gain Bandwidth Product	V <sub>CE</sub> = -10V, I <sub>C</sub> = - 0.75A	25		MHz
C <sub>ob</sub>	Output Capacitance	V <sub>CB</sub> = - 10V, I <sub>E</sub> = 0 f= 0.1MHz		200	pF

\* Pulse Test: PW≤300µs, Duty Cycle≤2%

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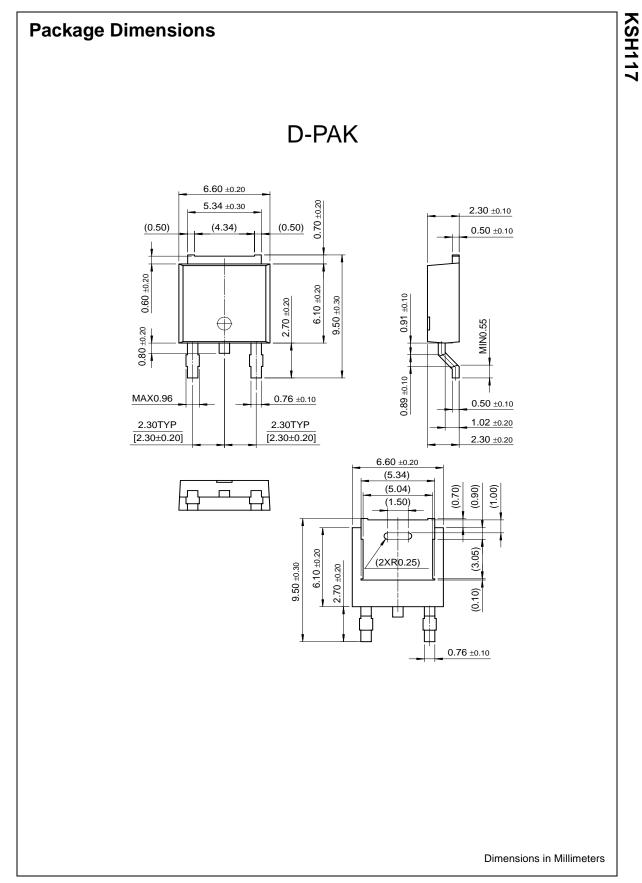


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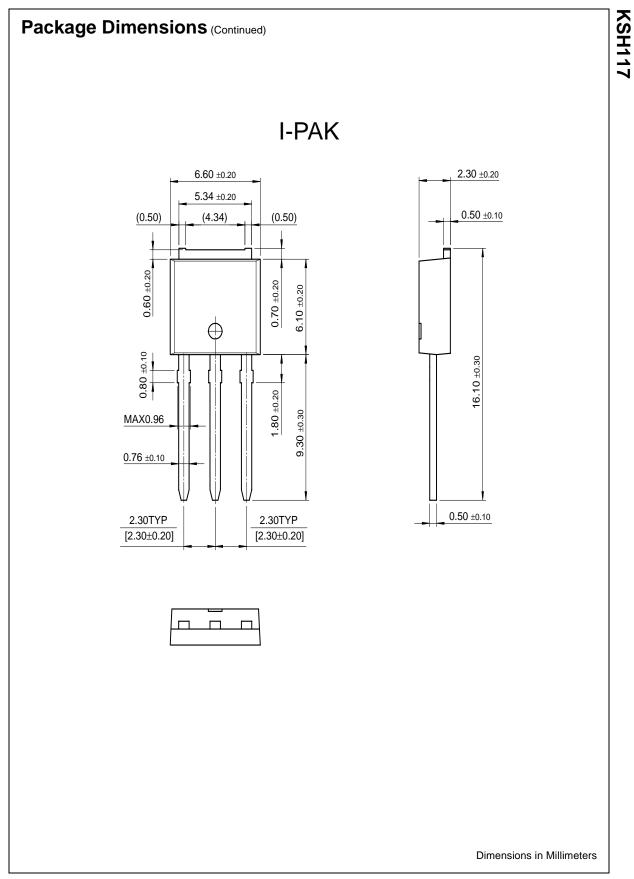


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